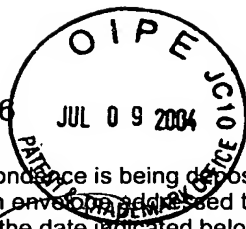


Docket No.: P2001,0126



1fw

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage as First Class Mail in an envelope addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on the date indicated below.

By: 

Date: July 6, 2004

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applic. No. : 10/647,614 Confirmation No: 2856  
Applicant : Ulrich Baier  
Filed : August 25, 2003  
Title : Method for Etching a Hard Mask Layer and a Metal Layer  
Art Unit : 2823  
Examiner : Joannie A. Garcia

Docket No. : P2001,0126  
Customer No. : 24131

INFORMATION DISCLOSURE STATEMENT  
UNDER 37 C.F.R. 1.97(i)

Hon. Commissioner for Patents

Sir:

In accordance with 37 C.F.R. 1.98 copies of the following patents and/or publications are submitted herewith:


United States Patent No. 6,235,214 B1 (Deshmukh et al.), dated May 22, 2001;

English translation of Taiwanese Office Action, dated May 11, 2004.

As per the Notice in 1273 OG 55 (August 5, 2003) no copies of any above-mentioned U.S. patents and U.S. patent application publications are submitted for any application filed after June 30, 2003.

It is believed that the enclosed prior art is less pertinent than the prior art previously submitted and cited by the Examiner. Kindly place the references in the Patent Office file wrapper.

Respectfully submitted,



For Applicant

Date: July 6, 2004

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FORM PTO-1449 (SUBSTITUTE)

U.S. DEPARTMENT OF COMMERCE  
PATENT AND TRADEMARK OFFICEAttorney Docket No.:  
P2001,0126Applic. No.  
10/647,614

Applicant

Ulrich Baier

Filing Date  
August 25, 2003Group Art Unit  
2823INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT  
(37 CFR 1.98(b))

## U.S. PATENT DOCUMENTS

EXAMINER INITIALS		PATENT NO.	DATE	PATENTEE	CLASS	SUB CLASS	FILING DATE
	A	6,235,214 B1	05/22/01	Deshmukh et al.			
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						

## FOREIGN PATENT DOCUMENT

		DOCUMENT NO.	DATE	COUNTRY	CLASS	SUB CLASS	TRANSL. YES   NO
	J						
	K						
	L						
	M						
	N						

## OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)

	O	
	P	

EXAMINER

DATE CONSIDERED

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609;  
Draw line through citation if not in conformance and not considered. Include copy of this form with  
next communication to applicant.